M5004 Series

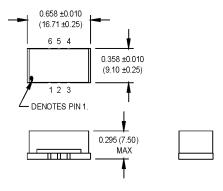
9x16 mm FR-4, 5.0 Volt, CMOS/TTL/PECL/LVDS, HPVCXO

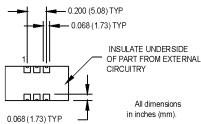


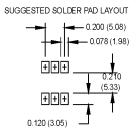




 Ideal for applications requiring long term (20 year) all-inclusive stability

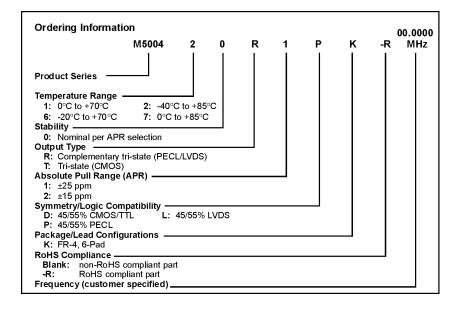






Pin Connections

PIN	FUNCTION			
1	Control Voltage			
2	Tristate			
3	Gro und			
4	Output 1			
5	N/C or Output 2			
6	+Vdd			



	PARAMETER	Symbol	Min.	Тур.	Max.	Units	Condition/Notes
	Frequency Range	F	10	- //-	30	MHz	CMOS/TTL/PECL/LVDS
	Operating Temperature	TA	(See Ordering Information)				
	Storage Temperature	Ts	-55	Γ	+105	°C	
	Frequency Stability	∆F/F	(See Ordering Information)				See Note 1
	Aging		(Ī	<u> </u>		
	1st Year				1.5	ppm	
	Thereafter (per year)				0.5	ppm	
	Pullability/APR		(See Ordering Information)				Over Control Voltage
	Control Voltage	Vc	0.5	2.5	4.5	٧	-
	Tuning Range				15	ppm/V	
	Modulation Bandwidth	fm	10			kHz	
۱.,	Input Impedance	Zin	50K			Ohms	
Suo	Input Voltage	Vcc/Vdd	4.75	5.0	5.25	V	
ati	Input Current	lcc/ldd	2		25	mA	CMOS/TTL
pecific			50		75	mA	PECL
			5		35	mA	LVDS
S	Output Type						CMOS/TTL/PECL/LVDS
Electrical Specifications	Load		2 TTL or 15 pF Max. 50 Ohms to Vcc -2 Volts 100 Ohm differential load (See Ordering Information)				CMOS/TTL PECL LVDS
Ш	Symmetry (Duty Cycle)						
	Output Skew				50	ps	PECL
	Differential Voltage		250	375	500	mV	LVDS
	Logic "1" Level	Voh	4.5			٧	CMOS/TTL
			3.9		4.1	V	PECL
l .			1.375			V	LVDS
	Logic "0" Level	Vol			0.5	V	CMOS/TTL
			3.1		3.4	V	PECL
					1.125	V	LVDS
	Rise/Fall Time	Tr/Tf	2.0		10	ns	CMOS/TTL
			0.25		3.0	ns	PECL/LVDS
	Tristate Function		Input Logic Input Logic				Opposite tristate logic Available upon request
	Start up Time		10 ms				
	Phase Noise (Typical)	10 Hz	100 Hz	1 kHz	10 kHz	100 kHz	Offset from carrier
	@ 19.44 MHz	-60	-90	-120	-135	-148	dBc/Hz

Stability includes initial tolerance, deviation over temperature, supply and load variation, and aging for 20 years @ 25°C.

MtronPTI reserves the right to make changes to the product(s) and service(s) described herein without notice. No liability is assumed as a result of their use or application.